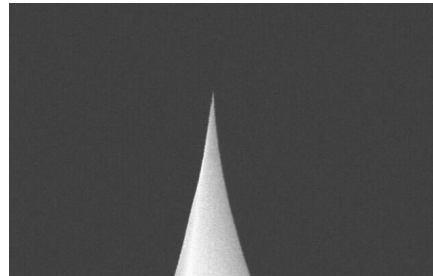


FORTA-SS

FORTA-SS probes are Super-Sharp silicon probes designed for Force Modulation applications. These probes have a medium frequency and spring constant that make them ideally suited to Force Modulation Microscopy, and have Aluminum coating on the reflex side to increase laser signal quality. Our Super Sharp probes yield enhanced resolution images.

Tip Specifications

- **Material:** Silicon
- **Shape:** Pyramidal
- **Height (μm):** 14-16
- **Aspect ratio:** >3.5
- **ROC (nm) :** 2
- **Coating:** None



FORTA-SS

On click zoom images

[Download Spec](#)

Cantilever Specifications

Material: Silicon

Shape : Rectangular

Reflex coating : Al, 50 nm \pm 5

Parameter	Nominal	Min	Max
k (N/m)	1.6	0.6	3.7
f (kHz)	61.0	43.0	81.0
Length (μm)	225.0	215.0	235.0
Width (μm)	27.0	22.0	32.0
Thickness (μm)	2.70	2.20	3.20